NOTES:

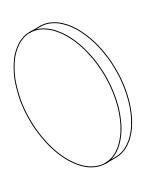
- 1. SUBSTRATE: UV FUSED SILICA
- 2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
- COATING (APPLY ACROSS COATING APERTURE) S1: HARD DIELECTRIC SPUTTERED T(avg): ≥91% FROM 433 - 1650nm @ 0° AOI T(avg): ≤0.01% FROM 200 - 415nm @ 0° AOI T(abs): =50% FOR 425±4.25nm @ 0° AOI

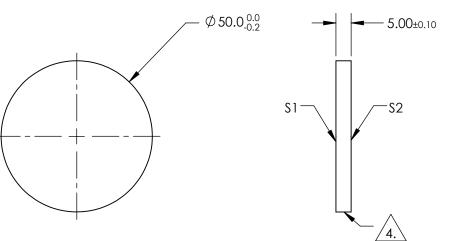
S2:SINGLE LAYER MgF2

4. FINE GRIND SURFACE

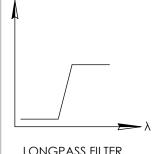
- 5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
- 6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm (prior to coating)
- 7. ROHS COMPLIANT







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SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE DIMENSIONS ARE FOR REFERENCE ONLY

LONGI 7 03 HEILK			_		Edmund Optics	R
	S1	S2				`
SHAPE	PLANO	PLANO			Ø50mm, 425nm, HIGH PERFORMANCE	:
SURFACE QUALITY	60-40	60-40		TITLE	LONGPASS FILTER	
CLEAR APERTURE	>80%	>80%				
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED	ALL DIMS IN mm	DWG NO		Sheet I of 1